Ref	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L5	234	324/767.cor.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 09:19
L6	45	324/770.ccls. and diode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 09:28
L7	41925	(test\$4 or measur\$4 or detect\$4 or determi\$4) same (light adj emitting adj diode)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR .	ON .	2005/08/16 09:29
L8	450	7 and (defect same diode)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 09:30
L9	2101	7 and (diode).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 09:30
L10	66	8 and (diode).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/16 09:31
S1	80797	g09g 3/32 .ipc.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 15:48
S2	1385	S1 and (light adj emitting adj diode)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:11

S3	193	S2 and (measur\$4 or test\$4 or detect\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 15:50
S4	0	S3 and (defect and mode)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:10
S5	1121685	S3 voltage and current	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 15:50
S6	145	S2 and (measur\$4 or test\$4 or detect\$4) and display	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 15:50
S7	3	S3 and (defect)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:10
S8	. 11	S1 and (light adj emitting adj diode) and defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:32
S9	1	"20050017922".pn. and defect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:33
S10	0	"20050017922".pn. and error	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 16:34

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S11		"20050017922".pn. and fault	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR .	ON	2005/08/15 16:34
S12	1	"20050017922".pn. and signal	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 17:21
S13	6	(light adj emitting adj diode) same (defect near3 mode)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 17:23
S14	8	(light adj emitting adj diode) same (defect near6 mode)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 17:24
S15	948	(light adj emitting adj diode) same (defect)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 17:24
S16	593	S15 and (measur\$4 or test\$4 or detect\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 17:25
S17	242	S16 and voltage and current	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 17:25
S18	132	S17 and (display or image)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/15 17:26

S19 18 S17 and (display or image).ti.							
	S19	18	S17 and (display or image).ti.	USPAT; USOCR; EPO; JPO; DERWENT;	OR	ON	2005/08/16 08:54